

NN51V16165A / NN51V18165A series
EDO (Hyper Page) Mode
CMOS 1M × 16bit Dynamic RAM



DESCRIPTION

Preliminary Specification

The NN51V16165A/18165A series is a high performance CMOS Dynamic Random Access Memory organized as 1,048,576 words by 16 bits. The NN51V16165A/18165A series is fabricated with advanced CMOS technology and designed with innovative design techniques resulting in high speed, extremely low power and wide operating margins at both component and system levels.

The NN51V16165A/18165A series features an EDO (Hyper Page) mode operation in which a high speed read, write or read-write is performed on any column address along a row address.

An extremely short row address capture time and an asynchronous column address decoder relax the timing constraints associated with address multiplexing.

Refresh is accomplished by performing RAS only refresh cycles, hidden refresh cycles, $\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ refresh cycles, or normal read or write cycles on the 4096 address combinations of A0 to A11 during a 64 ms period for NN51V16165A series and the 1024 address combination of A0 to A9 during a 16 ms period for NN51V18165A series.

Multiplexed address inputs permit the NN51V16165A/18165A series to be packaged in a standard 42-pin plastic SOJ, 50-pin plastic TSOP TYPE II. The package sizes provide high system bit densities. System level features include single power supply of 3.3V ±10% tolerance and direct interface with high performance TTL logic families.

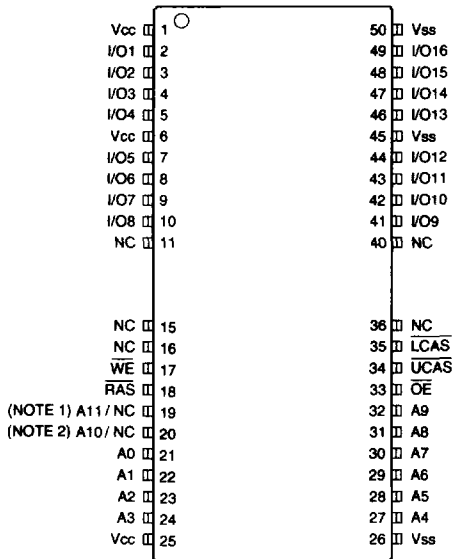
FEATURES

- 1,048,576 × 16 bit Organization
- Single 3.3V ±10% Power Supply
- Performance Ranges

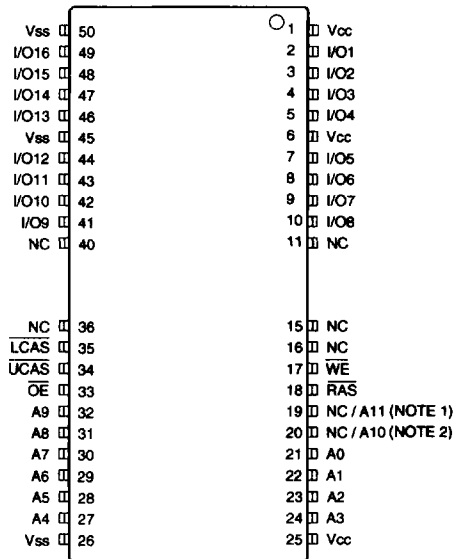
Parameter	-60	-70
Max. $\overline{\text{RAS}}$ Access Time (t_{RAC})	60ns	70ns
Max. $\overline{\text{CAS}}$ Access Time (t_{CAC})	15ns	20ns
Max. Column Address Access Time (t_{AA})	30ns	35ns
Min. Read/Write Cycle Time (t_{RC})	110ns	130ns

- EDO (Hyper Page) Mode Operation
- Separate CAS (UCAS, LCAS) for Byte Selection
- Byte Read/Write Mode Operation
- Low Power Operation
 - Low Standby Current (CMOS level input)
 - Standard 1mA
 - L version 150μA
- 4096 Refresh Cycles (NN51V16165A)
 - Standard 64ms
 - L version 128ms
- 1024 Refresh Cycles (NN51V18165A)
 - Standard 16ms
 - L version 128ms
- Self Refresh Mode (L version)
- All inputs/Outputs and Clocks fully TTL and CMOS compatible
- Refresh Modes
 - RAS only
 - $\overline{\text{CAS}}$ before $\overline{\text{RAS}}$
 - Hidden Refresh
- High Reliability Package
 - Plastic 42pin SOJ (P42SJ-2B0)
 - Plastic 50pin TSOP TYPE II (P50TP-3B6)

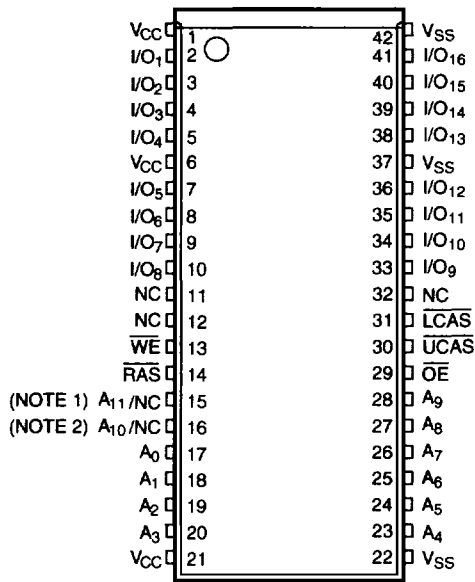
PIN CONFIGURATION



50/44-pin TSOP TYPE (I)
Normal Bend (400mil)
P50TP-3B6



50/44-pin TSOP TYPE (II)
Reverse Bend (400mil)
P50TP-3B6-R



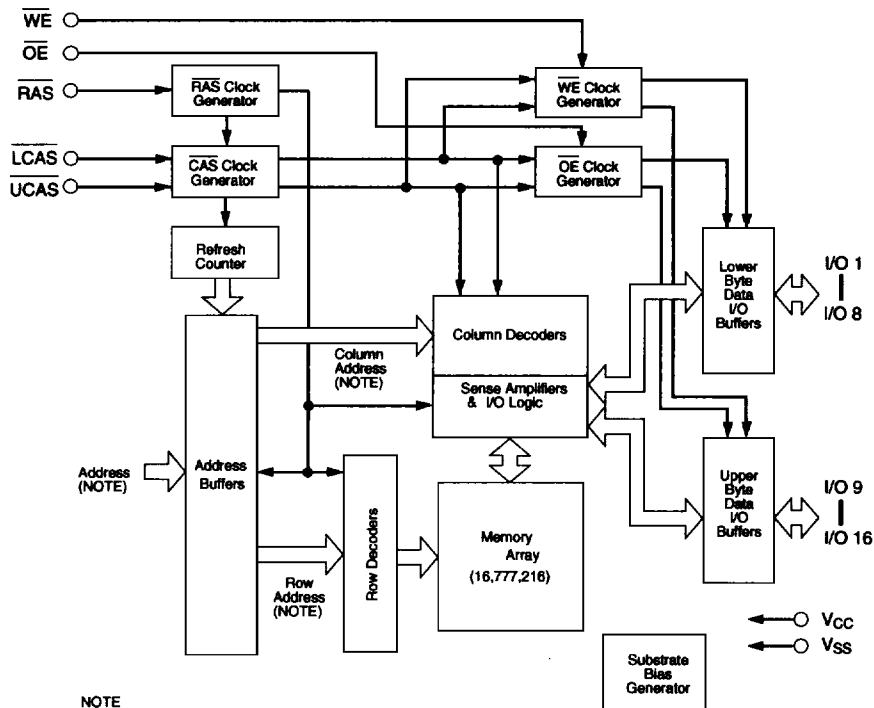
42-pin SOJ (400mil)
P42SJ-2B0

	NN51V16165A	NN51V18165A
NOTE 1	A11	NC
NOTE 2	A10	NC

PIN NAMES

A0-A11	Address Inputs (NOTE 1,2)
RAS	Row Address Strobe
UCAS	Column Address Strobe Upper Byte Control
LCAS	Column Address Strobe Lower Byte Control
OE	Output Enable
I/O1-I/O16	Data-in / Data-out
WE	Write Enable
Vcc	+3.3V Supply
Vss	Ground
NC	No Connection

FUNCTIONAL BLOCK DIAGRAM



NOTE

	Address / Row Address	Column Address
NN51V16165A	A0 - A11	A0 - A7
NN51V18165A	A0 - A9	A0 - A9

ABSOLUTE MAXIMUM RATINGS

RATING	SYMBOL	VALUE	UNIT
Voltage on Any Pin Relative to V _{SS}	V _{in} , V _{out}	-0.5 to 4.6	V
Voltage on V _{CC} Relative to V _{SS}	V _{CC}	-0.5 to 4.6	V
Storage Temperature (Plastic)	T _{stg}	-55 to +125	°C
Power Dissipation	P _d	1.0	W
Ambient Operating Temperature	T _a	0 to +70	°C
Short Circuit Output Current	I _{out}	20	mA

Permanent device damage can occur if absolute maximum ratings are exceeded. Functional operation should be restricted to the conditions as detailed in the operational sections of this data sheet. Exposure to absolute maximum rating conditions for extended periods can affect device reliability.

DC OPERATING CONDITIONS

SYMBOL	PARAMETER	MIN.	TYP.	MAX.	UNIT
V _{CC}	Supply Voltage	3.0	3.3	3.6	V
V _{SS}	Supply Voltage	0	0	0	V
V _{IH}	Input High Voltage, All Inputs	2.0	—	V _{CC} + 0.3	V
V _{IL}	Input Low Voltage, All Inputs	-0.3	—	0.8	V

Note: All voltage values in this data sheet are with respect to V_{SS} unless otherwise specified.

TRUTH TABLE

INPUTS					I/O		OPERATION	NOTES
RAS	LCAS	UCAS	WE	OE	I/O1~I/O8	I/O9~I/O16		
H	H	H	H	H	High-Z	High-Z	Standby	1,3
L	H	H	H	H	High-Z	High-Z	Refresh	1,3
L	L	H	H	L	Dout	High-Z	Lower byte read	1,3
L	H	L	H	L	High-Z	Dout	Upper byte read	1,3
L	L	L	H	L	Dout	Dout	Word read	1,3
L	L	H	L	H	Din	Don't care	Lower byte write	1,2,3
L	H	L	L	H	Don't care	Din	Upper byte write	1,2,3
L	L	L	L	H	Din	Din	Word write	1,2,3
L	L	L	H	H	High-Z	High-Z		1,3
H→L	L	H	—	—	High-Z	High-Z	CBR refresh or Self refresh	1,3
H→L	H	L	—	—	High-Z	High-Z		
H→L	L	L	—	—	High-Z	High-Z		

Notes: 1. H:high (inactive) , L:low (active) , —:unconcerned with H or L.

2. $t_{wcs} \geq 0ns$: early write mode.

$t_{wcs} < 0ns$: OE controlled write mode.

3. Operation mode is set by the earliest of LCAS and UCAS active edge and reset by the latest of LCAS and UCAS inactive edge.

However write operation and High-Z control are done independently by each LCAS, UCAS.

DC ELECTRICAL CHARACTERISTICS (0°C ≤ Ta ≤ 70°C, V_{CC} = 3.3V ±10%)

NN51V16165A

SYMBOL	PARAMETER	SPEED	MIN.	MAX.	UNIT	TEST CONDITIONS	NOTES
I _{CC1}	Operating Current	-60		100	mA	t _{RC} = t _{RC} (min.) RAS, CAS, Address cycling	1, 2
		-70		90	mA		
I _{CC2}	Standby Current			1.0	mA	RAS = $\overline{\text{CAS}} \geq (V_{CC} - 0.2V)$	
				2.0	mA	RAS = $\overline{\text{CAS}} \geq V_{IH}$	
	Standby Current (L version)			150	μA	RAS = $\overline{\text{CAS}} \geq (V_{CC} - 0.2V)$ All other inputs are stable at (V _{CC} - 0.2V) or (V _{SS} + 0.2V)	
I _{CC3}	Refresh Current (RAS only refresh)	-60		100	mA	t _{RC} = t _{RC} (min.) RAS cycling, $\overline{\text{CAS}} = V_{IH}$	1
		-70		90	mA		
I _{CC4}	EDO(Hyper Page) Mode Current	-60		110	mA	t _{HPC} = t _{HPC} (min.) RAS = V _{IL} CAS, Address cycling	1,2
		-70		100	mA		
I _{CC5}	Refresh Current (CAS before RAS refresh)	-60		100	mA	t _{RC} = t _{RC} (min.) RAS, CAS cycling	1
		-70		90	mA		
I _{CC6}	Refresh Current (L version : CAS before RAS refresh)			500	μA	4096 cycles / 128ms t _{RAS} ≤ 200ns, WE ≥ (V _{CC} - 0.2V) All other inputs are stable at (V _{CC} - 0.2V) or (V _{SS} + 0.2V)	
I _{CC7}	Self Refresh Mode Current (L version)			300	μA	RAS = $\overline{\text{CAS}} \leq (V_{SS} + 0.2V)$ All other input high levels are (V _{CC} - 0.2V) or input low levels are (V _{SS} + 0.2V)	
I _{L1}	Input Leakage Current (Any input pin)		-10	10	μA	0V ≤ V _{IH} ≤ 3.6V, Others = 0V	
I _{L0}	Output Leakage Current (For high impedance state)		-10	10	μA	RAS ≥ V _{IH} (min.), $\overline{\text{CAS}} \geq V_{IH}(\text{min.})$ 0V ≤ V _{OUT} ≤ 3.6V	
V _{OH}	Output High Voltage		2.4		V	I _{OH} = -2.0 mA	
V _{OL}	Output Low Voltage			0.4	V	I _{OL} = 2.0 mA	

Notes: 1. I_{CC1}, I_{CC3}, I_{CC4} and I_{CC5} depend on cycle rate.

2. I_{CC1} and I_{CC4} depend on output loading. Specified values are obtained with the outputs open.

CAPACITANCE (0°C ≤ Ta ≤ 70°C, V_{CC} = 3.3V ±10%, f = 1MHz)

SYMBOL	PARAMETER	MIN.	MAX.	UNIT
C _{IN1}	Address(A0 ~ A11)	—	5	pF
C _{IN2}	RAS, LCAS, UCAS, WE, OE	—	5	pF
C _{OUT}	I/O1 ~ I/O16	—	7	pF

DC ELECTRICAL CHARACTERISTICS (0°C ≤ Ta ≤ 70°C, V_{CC} = 3.3V ±10%)

NN51V18165A

SYMBOL	PARAMETER	SPEED	MIN.	MAX.	UNIT	TEST CONDITIONS	NOTES
I _{CC1}	Operating Current	-60		160	mA	t _{RC} = t _{RC} (min.) RAS, CAS, Address cycling	1, 2
		-70		140	mA		
I _{CC2}	Standby Current			1.0	mA	RAS = CAS ≥ (V _{CC} - 0.2V)	
				2.0	mA	RAS = CAS ≥ V _{IH}	
	Standby Current (L version)			150	μA	RAS = CAS ≥ (V _{CC} - 0.2V) All other inputs are stable at (V _{CC} - 0.2V) or (V _{SS} + 0.2V)	
I _{CC3}	Refresh Current (RAS only refresh)	-60		160	mA	t _{RC} = t _{RC} (min.) RAS cycling, CAS = V _{IH}	1
		-70		140	mA		
I _{CC4}	EDO(Hyper Page) Mode Current	-60		160	mA	t _{HPC} = t _{HPC} (min.) RAS = V _{IL} CAS, Address cycling	1,2
		-70		150	mA		
I _{CC5}	Refresh Current (CAS before RAS refresh)	-60		160	mA	t _{RC} = t _{RC} (min.) RAS, CAS cycling	1
		-70		140	mA		
I _{CC6}	Refresh Current (L version : CAS before RAS refresh)			500	μA	1024 cycles / 128ms t _{RAS} ≤ 200ns, WE ≥ (V _{CC} - 0.2V) All other inputs are stable at (V _{CC} - 0.2V) or (V _{SS} + 0.2V)	
I _{CC7}	Self Refresh Mode Current (L version)			300	μA	RAS = CAS ≤ (V _{SS} + 0.2V) All other input high levels are (V _{CC} - 0.2V) or input low levels are (V _{SS} + 0.2V)	
I _{I1}	Input Leakage Current (Any input pin)		-10	10	μA	0V ≤ V _{IH} ≤ 3.6V, Others = 0V	
I _{I0}	Output Leakage Current (For high impedance state)		-10	10	μA	RAS ≥ V _{IH} (min.), CAS ≥ V _{IH} (min.) 0V ≤ V _{OUT} ≤ 3.6V	
V _{OH}	Output High Voltage		2.4		V	I _{OH} = -2.0 mA	
V _{OL}	Output Low Voltage			0.4	V	I _{OL} = 2.0 mA	

- Notes: 1. I_{CC1}, I_{CC3}, I_{CC4} and I_{CC5} depend on cycle rate.
 2. I_{CC1} and I_{CC4} depend on output loading. Specified values are obtained with the outputs open.

CAPACITANCE (0°C ≤ Ta ≤ 70°C, V_{CC} = 3.3V ±10%, f = 1MHz)

SYMBOL	PARAMETER	MIN.	MAX.	UNIT
C _{IN1}	Address(A0 ~ A9)	—	5	pF
C _{IN2}	RAS, UCAS, LCAS, WE, OE	—	5	pF
C _{OUT}	I/O1 ~ I/O16	—	7	pF

A.C. OPERATING CONDITIONS (0 °C ≤ Ta ≤ 70 °C, V_{CC} = 3.3 V ± 10%, V_{SS} = 0 V) (NOTES 3, 4, 5)

NO.	NOTES		PARAMETER	-60		-70		UNIT	NOTE
	JEDEC	STD.		MIN.	MAX.	MIN.	MAX.		
1	t _{CL1QV}	t _{CAC}	Access Time from $\overline{\text{CAS}}$	—	15	—	20	ns	6,13
2	t _{CH2QV}	t _{CPA}	Access Time from $\overline{\text{CAS}}$ Precharge	—	35	—	40	ns	13,14
3	t _{AVQV}	t _{AA}	Access Time from Column Address	—	30	—	35	ns	7,13
4	t _{RL1QV}	t _{RAC}	Access Time from $\overline{\text{RAS}}$	—	60	—	70	ns	6,7
5	t _{RL1CH1}	t _{CSH}	$\overline{\text{CAS}}$ Hold Time	45	—	55	—	ns	
6	t _{RL1CX}	t _{CHS}	$\overline{\text{CAS}}$ Hold Time (Self Refresh Mode)	-50	—	-50	—	ns	
7	t _{RL1CH1}	t _{CHR}	$\overline{\text{CAS}}$ Hold Time ($\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ Refresh)	10	—	10	—	ns	
8	t _{CH2CL2}	t _{CPN}	$\overline{\text{CAS}}$ Precharge Time ($\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ Refresh)	10	—	10	—	ns	
9	t _{CH2CL2}	t _{CP}	$\overline{\text{CAS}}$ Precharge Time	5	—	5	—	ns	14
10	t _{CL1CH1}	t _{CAS}	$\overline{\text{CAS}}$ Pulse Width	10	100K	15	100K	ns	
11	t _{CL1RL2}	t _{CSR}	$\overline{\text{CAS}}$ Setup Time ($\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ Refresh)	5	—	5	—	ns	
12	t _{CL1QX}	t _{CLZ}	$\overline{\text{CAS}}$ to Output in Low-Z	0	—	0	—	ns	8
13	t _{CH2RL2}	t _{CRP}	$\overline{\text{CAS}}$ to $\overline{\text{RAS}}$ Precharge Time	5	—	5	—	ns	
14	t _{CL1WL2}	t _{CWD}	$\overline{\text{CAS}}$ to $\overline{\text{WE}}$ Delay Time	45	—	50	—	ns	11
15	t _{CL1AX}	t _{CAH}	Column Address Hold Time	15	—	15	—	ns	
16	t _{RL1AX}	t _{AR}	Column Address Hold Time Referenced to $\overline{\text{RAS}}$	40	—	40	—	ns	
17	t _{AVCL2}	t _{ASC}	Column Address Setup Time	0	—	0	—	ns	14
18	t _{AVCH1}	t _{CAL}	Column Address to $\overline{\text{CAS}}$ Lead Time	18	—	23	—	ns	
19	t _{AVRH1}	t _{RAL}	Column Address to $\overline{\text{RAS}}$ Lead Time	30	—	35	—	ns	
20	t _{AVWL2}	t _{AWD}	Column Address to $\overline{\text{WE}}$ Delay Time	60	—	65	—	ns	11
21	t _{CL1DX} t _{WL1DX}	t _{DH}	Data Hold Time	10	—	10	—	ns	12
22	t _{CL2QX}	t _{DHC}	Data Output Hold Time	0	—	0	—	ns	
23	t _{DVCL2} t _{DVWL2}	t _{DS}	Data Setup Time	0	—	0	—	ns	12
24	t _{OL1QV}	t _{OEa}	$\overline{\text{OE}}$ Access Time	—	15	—	20	ns	
25	t _{WL1OL2}	t _{OEh}	$\overline{\text{OE}}$ Command Hold Time	15	—	20	—	ns	
26	t _{GH2GL2}	t _{OPZ}	$\overline{\text{OE}}$ Pulse Width for Output Disable When $\overline{\text{CAS}}$ High	7	—	7	—	ns	
27	t _{GL1CH1}	t _{OCS}	$\overline{\text{OE}}$ Setup Time to $\overline{\text{CAS}}$ High	7	—	7	—	ns	
28	t _{GL1RH1}	t _{ORS}	$\overline{\text{OE}}$ Setup Time to $\overline{\text{RAS}}$ High	7	—	7	—	ns	
29	t _{CH2QV}	t _{OED}	$\overline{\text{OE}}$ to Data Delay Time	15	—	20	—	ns	
30	t _{GL2QX}	t _{OLZ}	$\overline{\text{OE}}$ to Output in low-Z	0	—	0	—	ns	
31	t _{CH2QZ}	t _{OFF}	Output Buffer Turn-off Delay Time	0	15	0	15	ns	10
32	t _{OH2QX}	t _{OEZ}	Output Buffer Turn-off Delay Time Referenced to $\overline{\text{OE}}$	0	15	0	15	ns	
33	t _{RHQZ}	t _{OFFR}	Output Buffer Turn-off Delay Time Referenced to $\overline{\text{RAS}}$	0	15	0	15	ns	16
34	t _{WL2QZ}	t _{WEZ}	Output Buffer Turn-off Delay Time Referenced to $\overline{\text{WE}}$	0	15	0	15	ns	

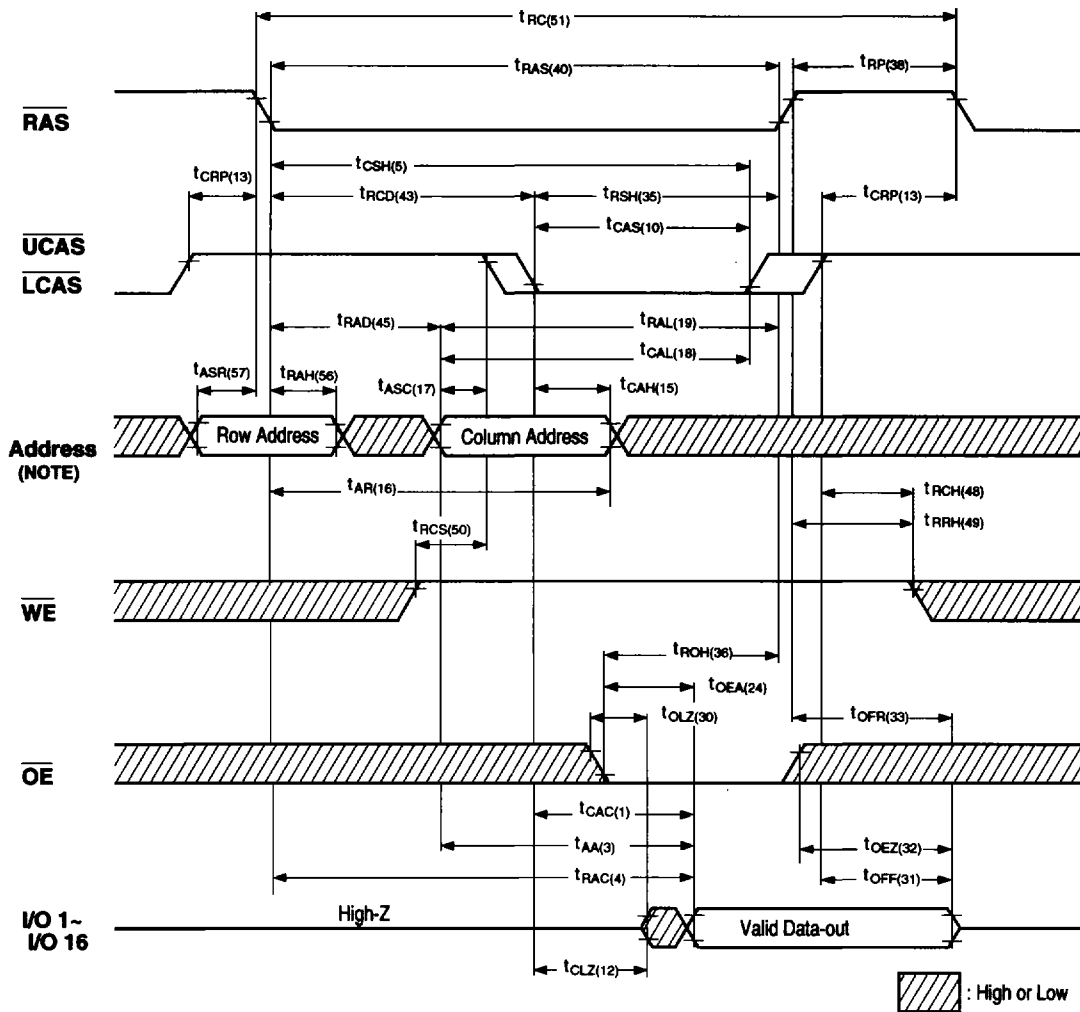
NN51V16165A / NN51V18165A series
CMOS 1M × 16 Dynamic RAM

NO.	SYMBOL		PARAMETER	-60		-70		UNIT	NOTE
	JEDEC	STD.		MIN.	MAX.	MIN.	MAX.		
35	t _{CL1RH1}	t _{RSH}	RAS Hold Time	15	—	20	—	ns	
36	t _{OL1RH1}	t _{ROH}	RAS Hold Time Referenced to OE	10	—	10	—	ns	
37	t _{CH2RH1}	t _{RHCP}	RAS Hold Time Referenced CAS Precharge	35	—	40	—	ns	
38	t _{RH2RL2}	t _{RP}	RAS Precharge Time	30	—	40	—	ns	
39	t _{RH2RL2}	t _{RPS}	RAS Precharge Time (Self Refresh Mode)	110	—	130	—		
40	t _{RL1RH1}	t _{RAS}	RAS Pulse Width	60	100K	70	100K	ns	
41	t _{RL1RH1}	t _{RASS}	RAS Pulse Width (Self Refresh Mode)	300	—	300	—	μs	
42	t _{RL1RH1}	t _{RASP}	RAS Pulse Width (EDO (Hyper Page) Mode)	60	100K	70	100K	ns	
43	t _{RL1CL1}	t _{RCD}	RAS to CAS Delay Time	13	45	13	50	ns	6
44	t _{RH2CL2}	t _{RPC}	RAS to CAS Precharge Time	0	—	0	—	ns	
45	t _{RL1AV}	t _{RAD}	RAS to Column Address Delay Time	11	30	11	35	ns	7
46	t _{RL2OX}	t _{RLZ}	RAS To Output in Low-Z	0	—	0	—	ns	
47	t _{RL1WL2}	t _{RWD}	RAS to WE Delay Time	90	—	100	—	ns	11
48	t _{CH2WL2}	t _{RCH}	Read Command Hold Time	0	—	0	—	ns	9
49	t _{RH2WL2}	t _{RRH}	Read Command Hold Time Referenced to RAS	0	—	0	—	ns	9
50	t _{WH2CL2}	t _{RCS}	Read Command Setup Time	0	—	0	—	ns	
51	t _{RL2RL2}	t _{RC}	Random Read or Write Cycle Time	110	—	130	—	ns	
52	t _{CL2CL2}	t _{HPC}	Read or Write Cycle Time (EDO (Hyper Page) Mode)	25	—	30	—	ns	13,14
53	t _{RL2RL2}	t _{RMW}	Read-Modify-Write Cycle Time	165	—	185	—	ns	
54	t _{CL2CL2}	t _{PRMW}	Read-Modify-Write Cycle Time (EDO (Hyper Page) Mode)	85	—	95	—	ns	13,14
55	t _{REF}	t _{REF}	Refresh Period	—	64	—	64	ms	15
			NN51V16165A	—	16	—	16		
			NN51V18165A	—	16	—	16		
56	t _{RL1AX}	t _{RAH}	Row Address Hold Time	10	—	10	—	ns	
57	t _{AVRL2}	t _{ASR}	Row Address Setup Time	0	—	0	—	ns	
58	t _T	t _T	Transition Time (Rise and Fall)	2	50	2	50	ns	4,5
59	t _{WL1WH1}	t _{WPZ}	WE Pulse Width for Disable When CAS High	7	—	7	—	ns	
60	t _{CL1WH1}	t _{WCH}	Write Command Hold Time	10	—	15	—	ns	
61	t _{WL1WH1}	t _{WP}	Write Command Pulse Width	10	—	15	—	ns	
62	t _{WL1CL2}	t _{WCS}	Write Command Setup Time	0	—	0	—	ns	11
63	t _{WL1CH1}	t _{CWL}	Write Command to CAS Lead Time	15	—	20	—	ns	
64	t _{WL1RH1}	t _{RWL}	Write Command to RAS Lead Time	15	—	20	—	ns	

Notes:

3. Eight Initialization Cycles are required following a 200 μ s pause after Power Up. These Initialization Cycles may consist of one of the following : RAS only refresh Cycles, Read Cycles, Write Cycles, $\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ refresh Cycles.
4. AC measurements assume $t_T=3\text{ns}$. All AC parameters are measured with $V_{IL}(\text{min.})\geq V_{SS}$ and $V_{IH}(\text{max.})\leq V_{CC}$ and with a load equivalent to two TTL loads and 100pF.
5. $V_{IH}(\text{min.})$ and $V_{IL}(\text{max.})$ are reference levels for measuring timing of input signals. Also, transition times are measured between V_{IH} and V_{IL} .
6. Operation within the $t_{RCD}(\text{max.})$ limit ensures that $t_{RAC}(\text{max.})$ can be met. $t_{RCD}(\text{max.})$ is specified as a reference point only. If t_{RCD} is greater than the specified $t_{RCD}(\text{max.})$ limit, then access time is controlled by t_{CAC} .
7. Operation within the $t_{RAD}(\text{max.})$ limit ensures that $t_{RAC}(\text{max.})$ can be met. $t_{RAD}(\text{max.})$ is specified as a reference point only. If t_{RAD} is greater than the specified $t_{RAD}(\text{max.})$ limit, then access time is controlled by t_{AA} .
8. Assumes three state test load (5pF and a 220 ohm to 1.3V Thevenin equivalent).
9. Either t_{RCH} or t_{RRH} must be satisfied for a read cycle.
10. $t_{OFF}(\text{max.})$ defines the time at which the output achieves an open circuit condition and is not referenced to output voltage levels.
11. t_{WCS} , t_{RWD} , t_{CWD} and t_{AWD} are not restrictive operating parameters. They are included in the data sheet as electrical characteristics only. If $t_{WCS}\geq t_{WCS}(\text{min.})$, the cycle is an early write cycle and data-out pins will remain open circuit (high impedance) throughout the entire cycle. If $t_{RWD}\geq t_{RWD}(\text{min.})$, $t_{CWD}\geq t_{CWD}(\text{min.})$ and $t_{AWD}\geq t_{AWD}(\text{min.})$, the cycle is a read-modify-write cycle and the data-out will contain data read from the selected cell. If neither of the above conditions is satisfied, the condition of the data-out (at access time) is indeterminate.
12. These parameters are referenced to $\overline{\text{CAS}}$ leading edge in early write cycles and to $\overline{\text{WE}}$ leading edge in read-modify-write cycles.
13. Access time is determined by the longer of t_{AA} , t_{CAC} , or t_{CPA} .
14. $t_{ASC}\geq t_{CP}$ to achieve $t_{PC}(\text{min.})$ and $t_{CPA}(\text{max.})$ values.
15. $t_{REF}=128\text{msec}$ for Long Refresh version (L version).
16. t_{OFF} applies only when $\overline{\text{CAS}}$ is high.

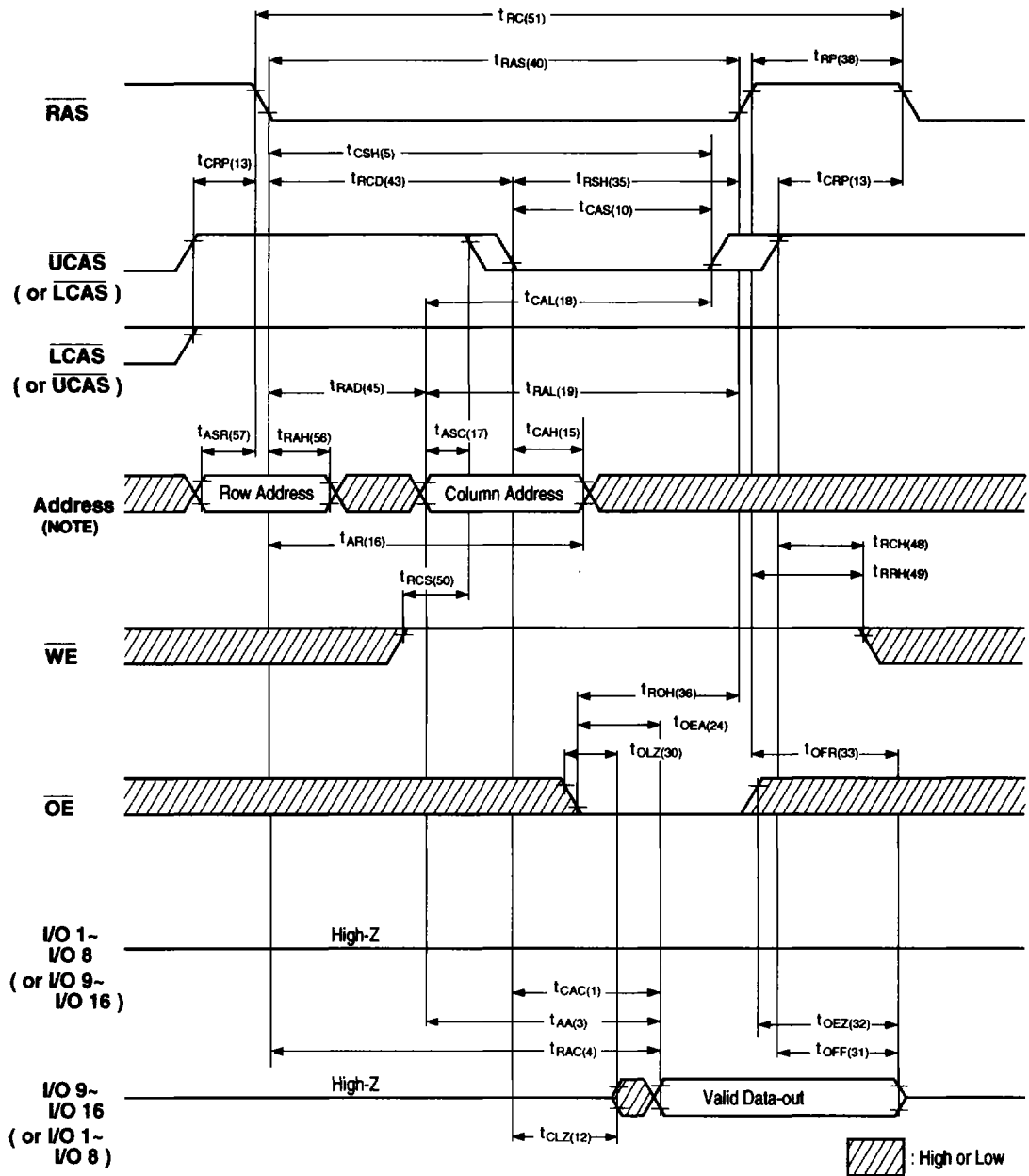
WORD READ CYCLE



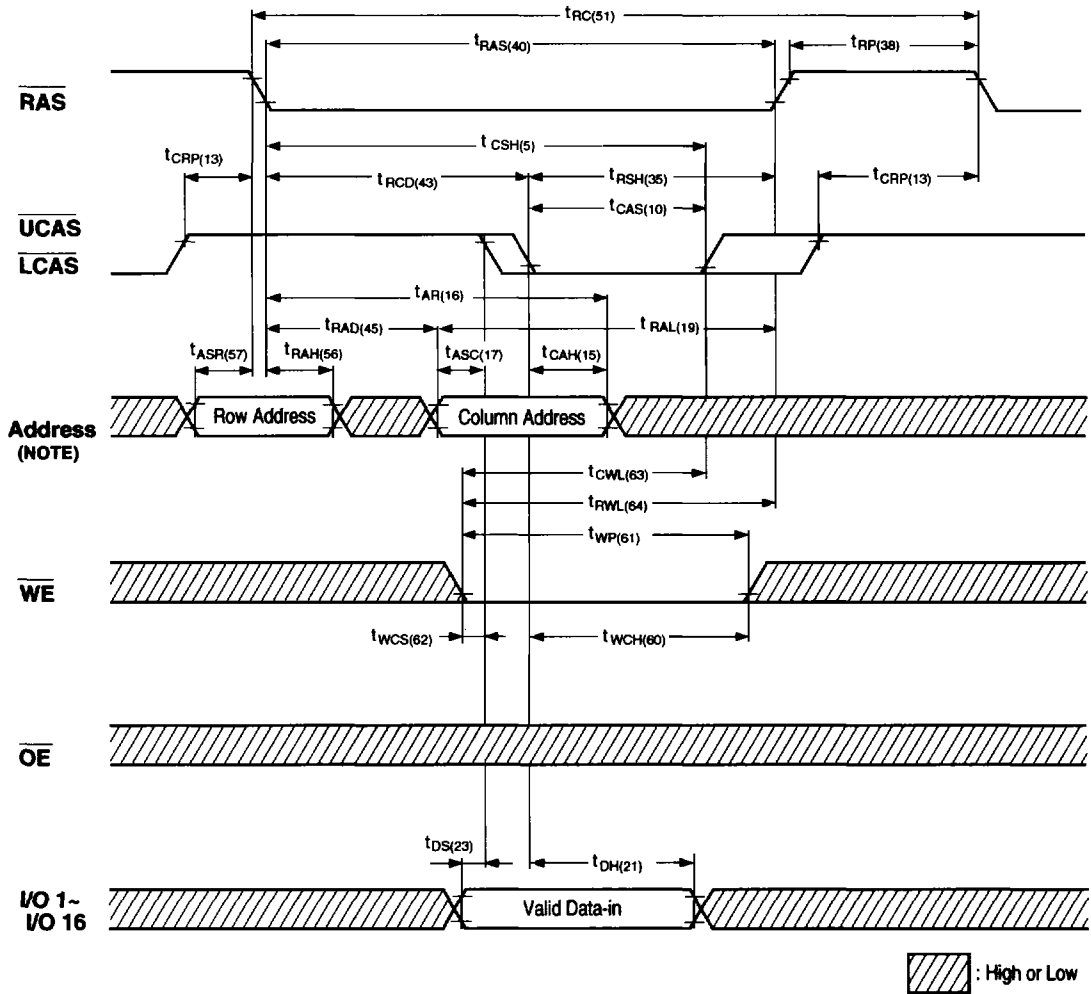
NOTE

Address A0 - A11: NN51V16165A
 A0 - A9: NN51V18165A

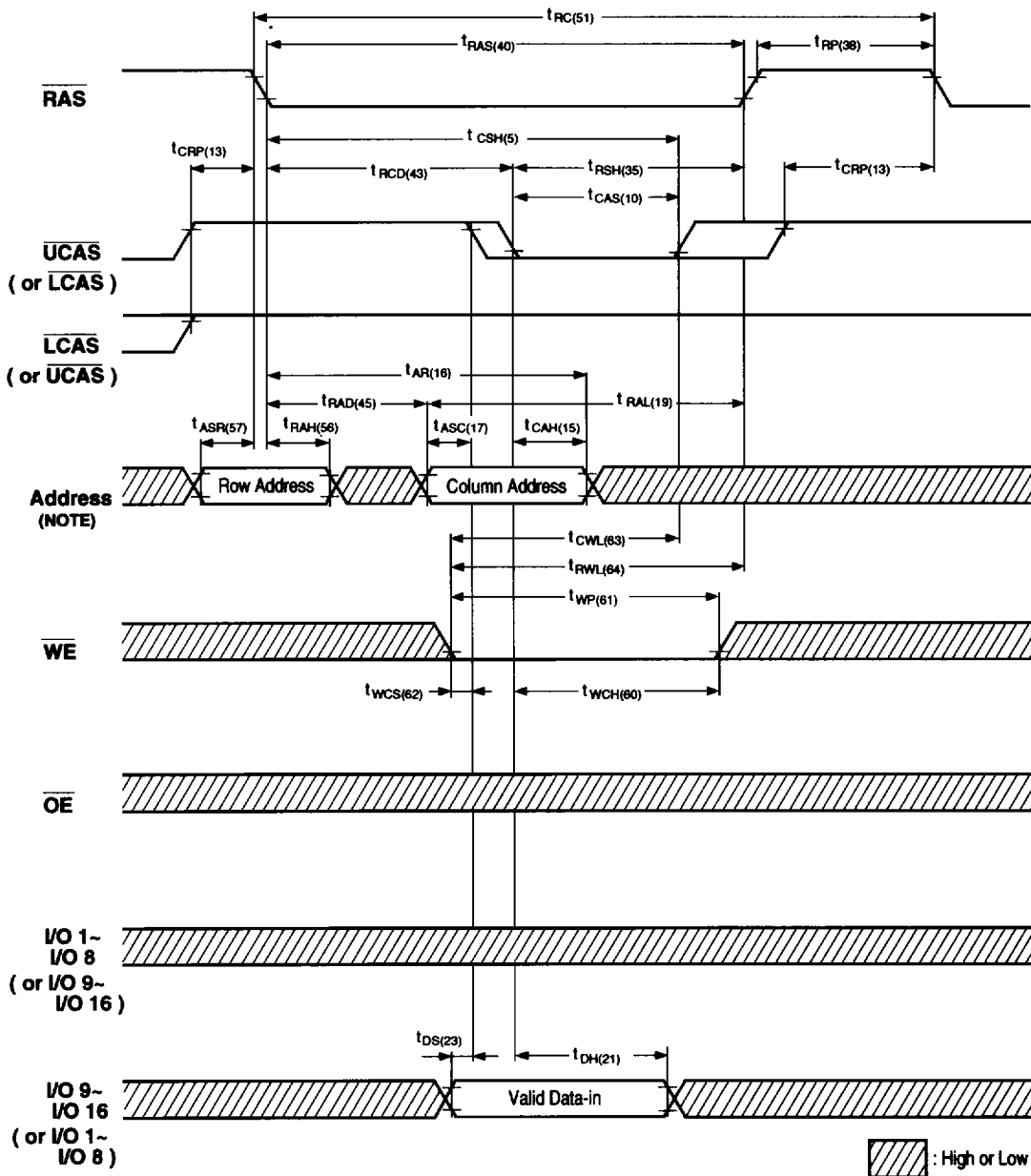
BYTE READ CYCLE



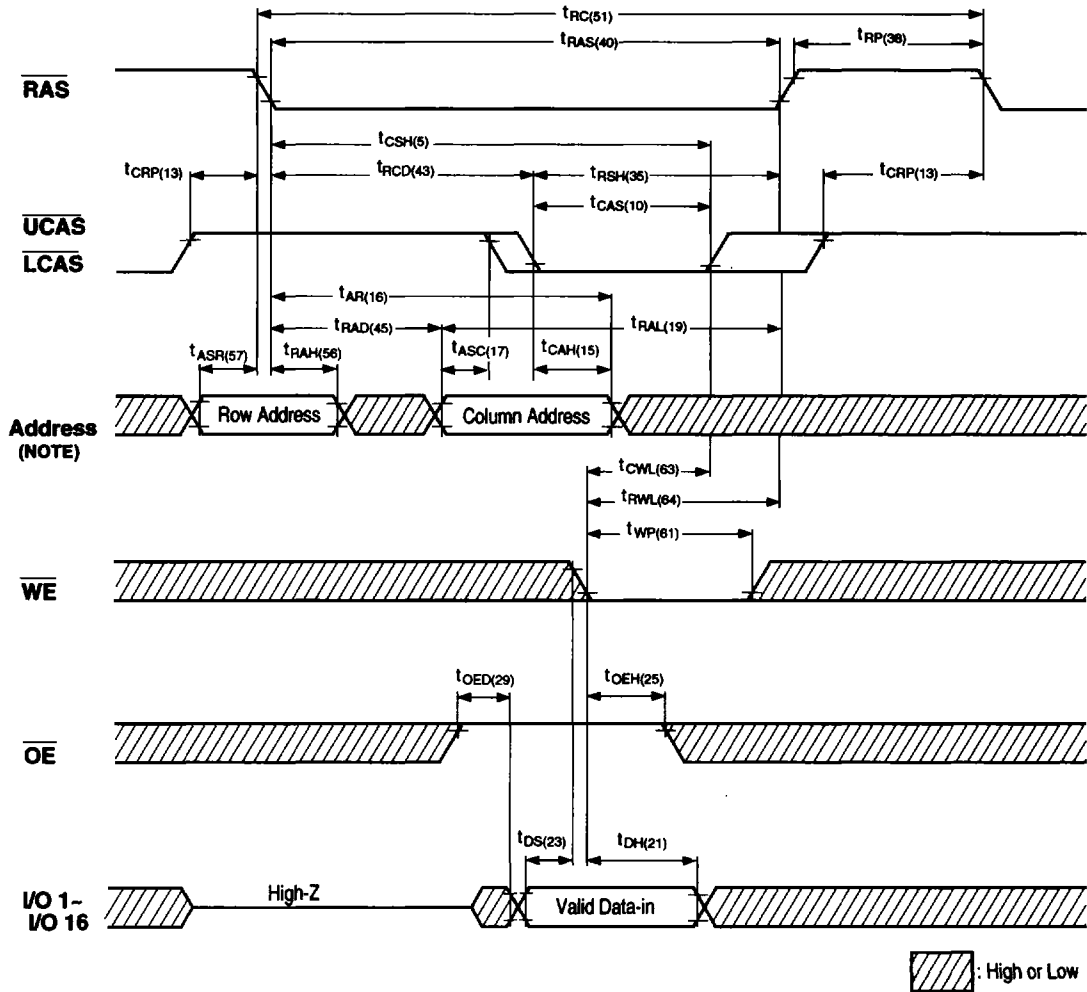
WORD WRITE CYCLE (EARLY WRITE)



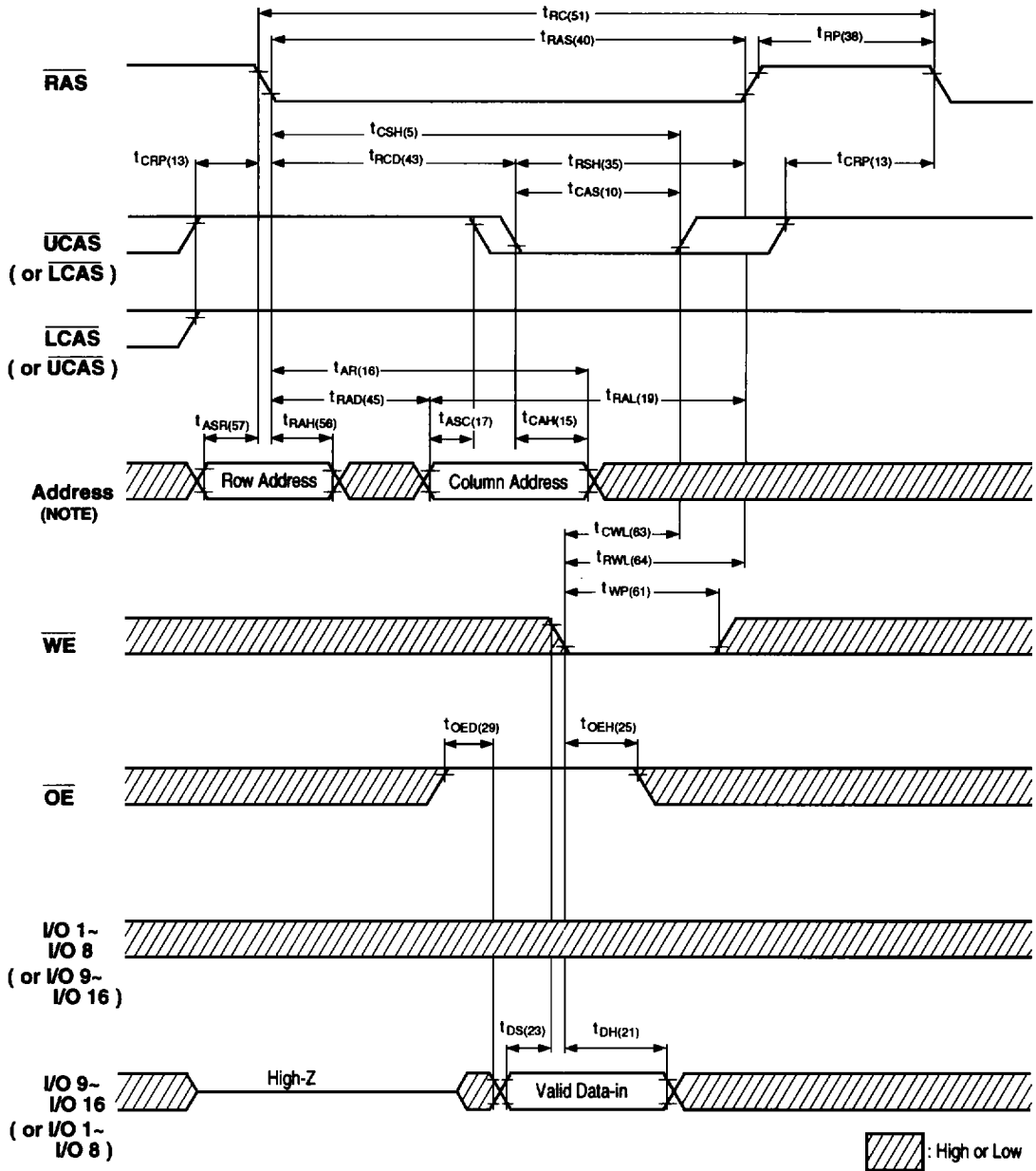
BYTE WRITE CYCLE (EARLY WRITE)



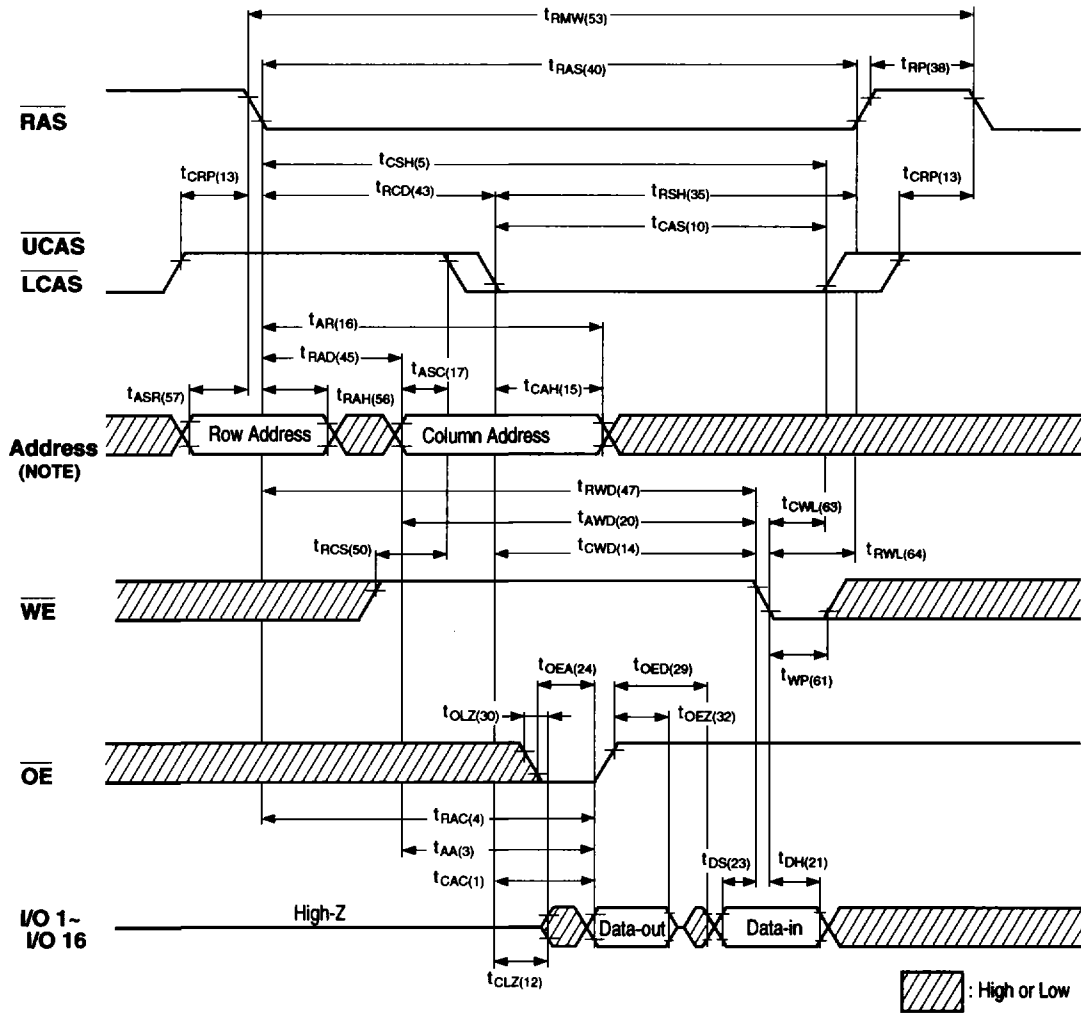
WORD WRITE CYCLE ($\overline{\text{OE}}$ -CONTROLLED WRITE)



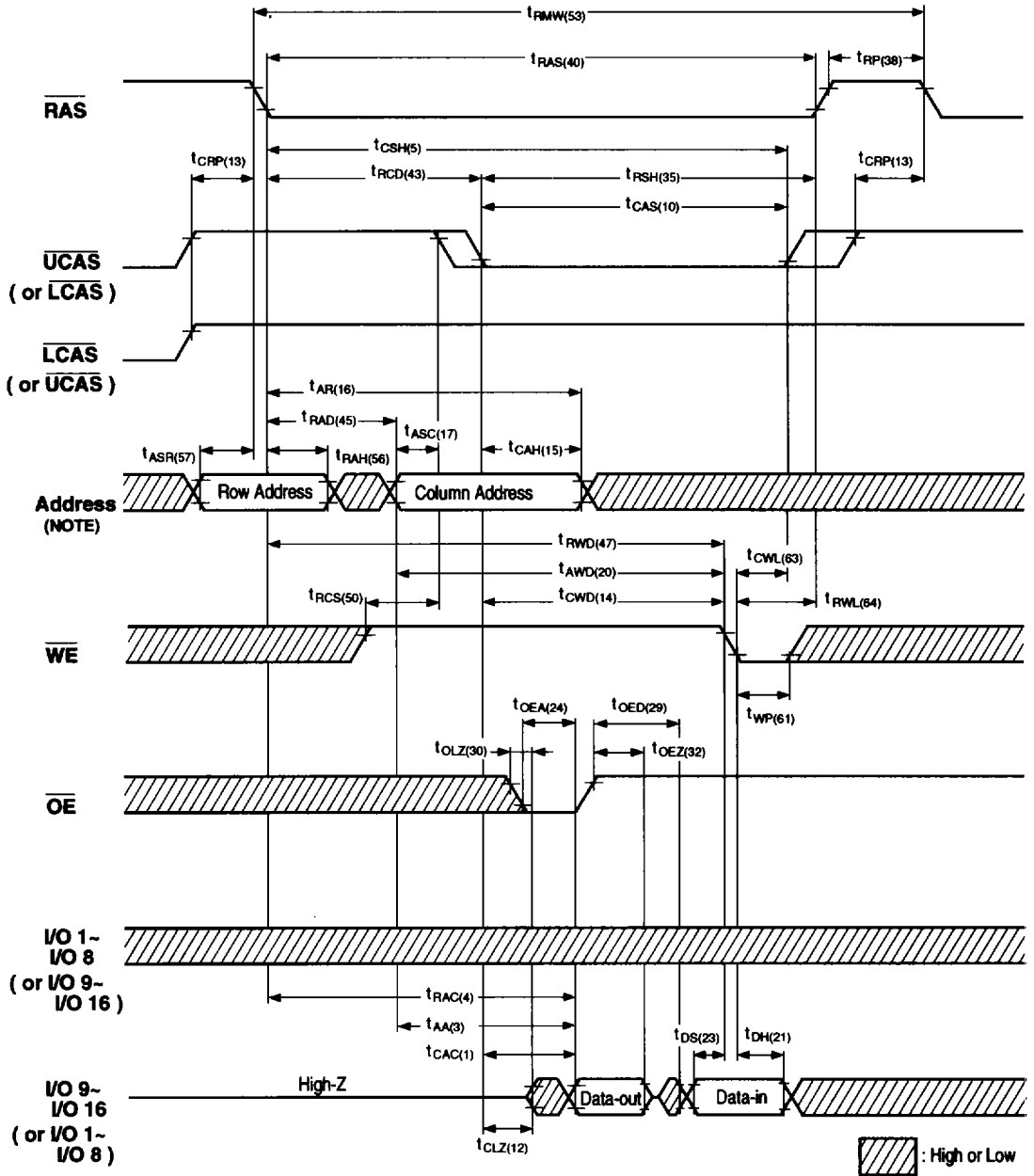
BYTE WRITE CYCLE (OE-CONTROLLED WRITE)



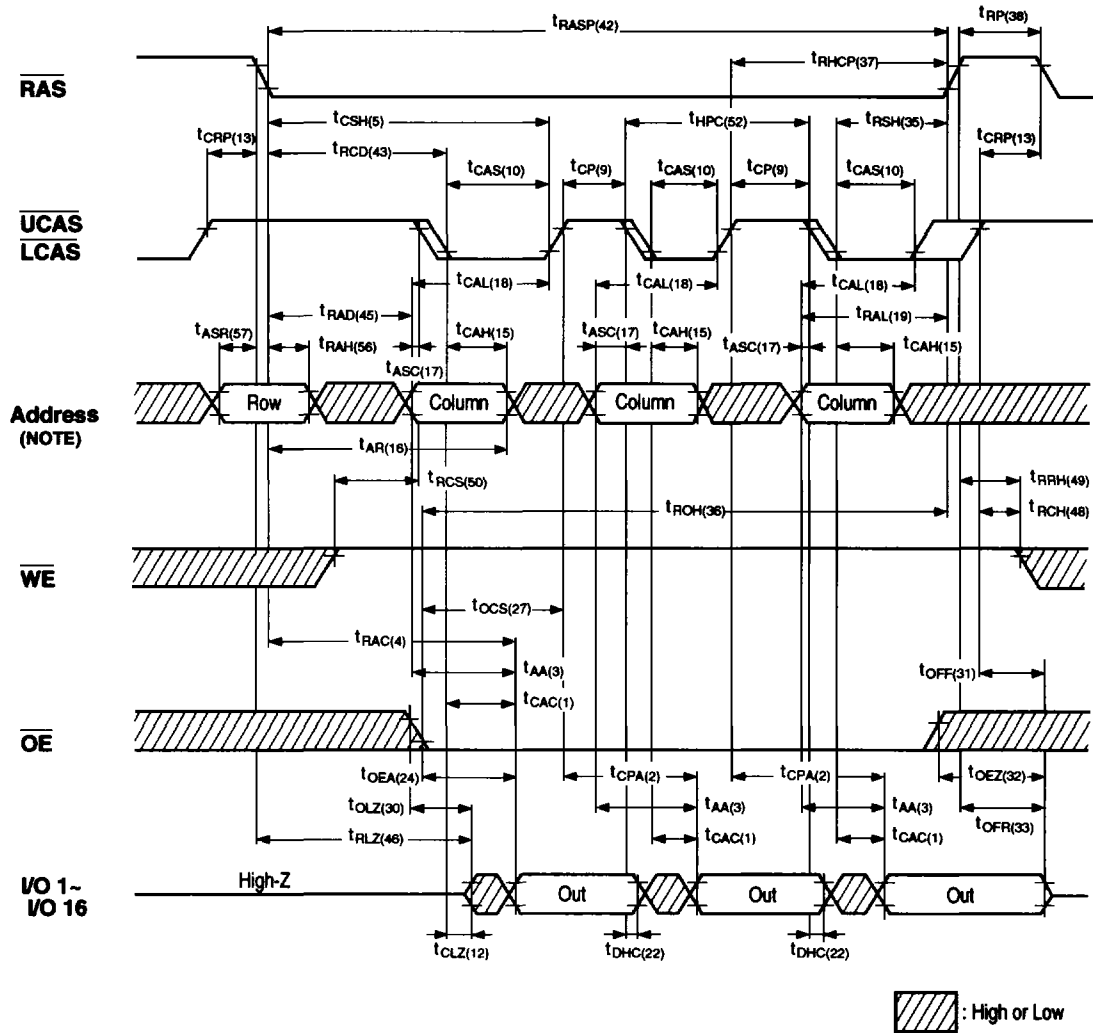
WORD READ-MODIFY-WRITE CYCLE



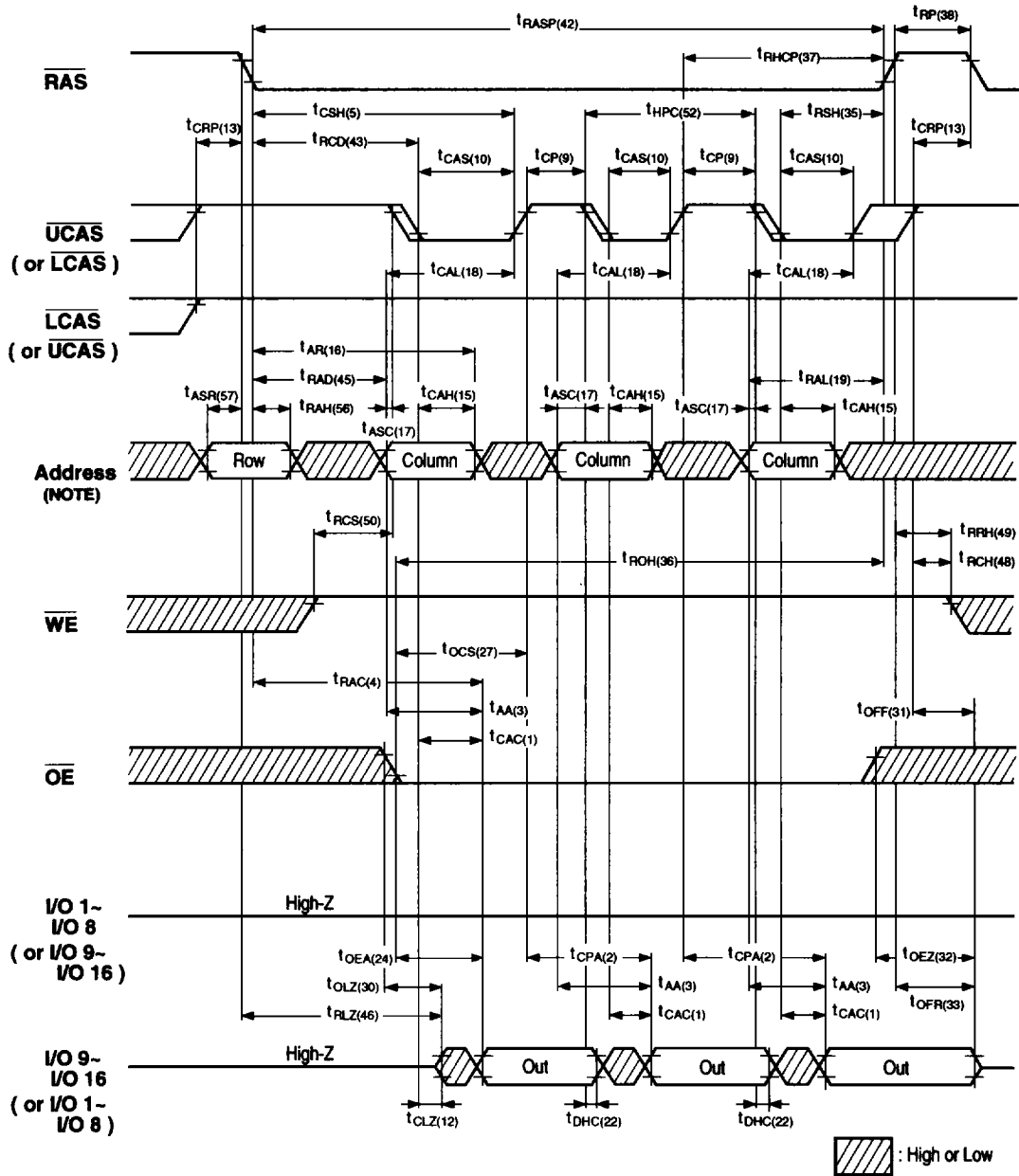
BYTE READ-MODIFY-WRITE CYCLE



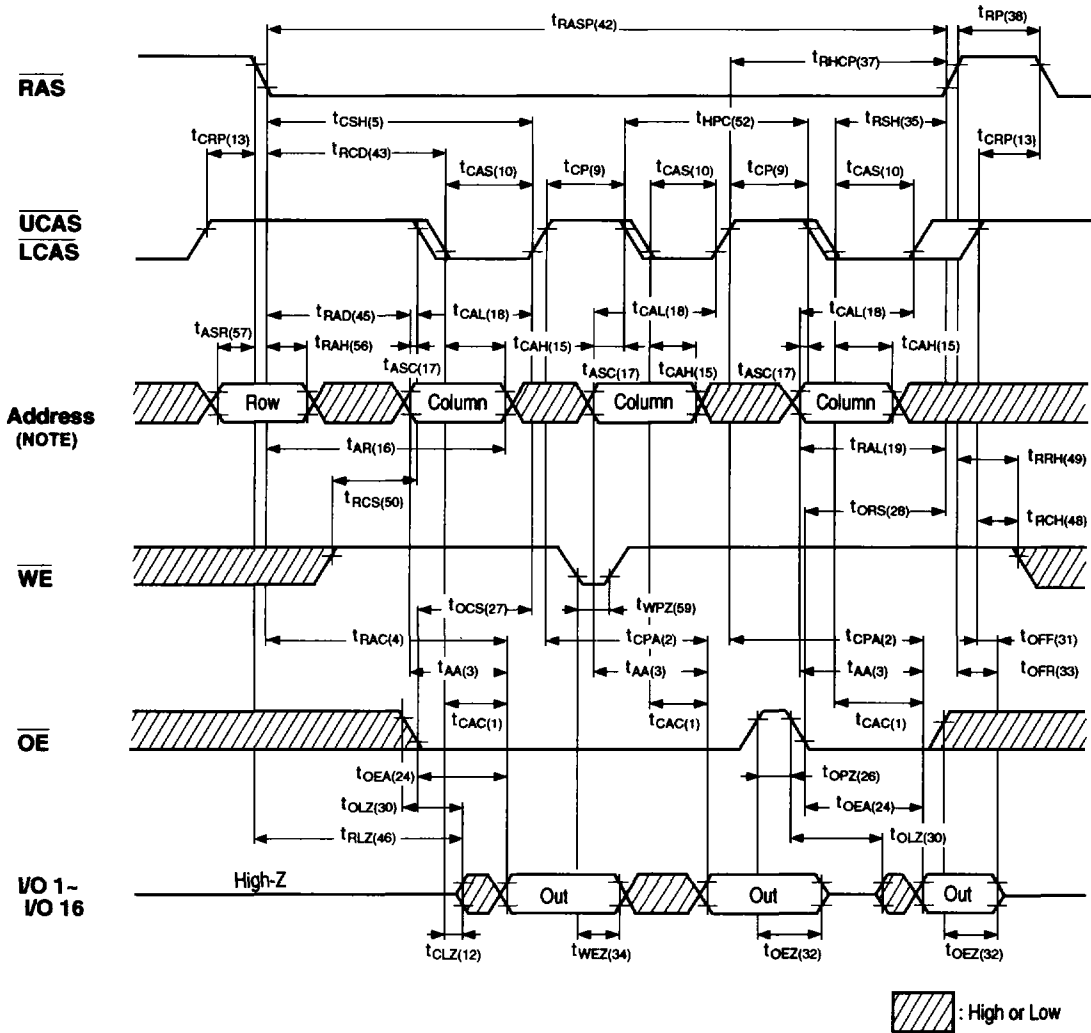
EDO (HYPER PAGE) MODE WORD READ CYCLE



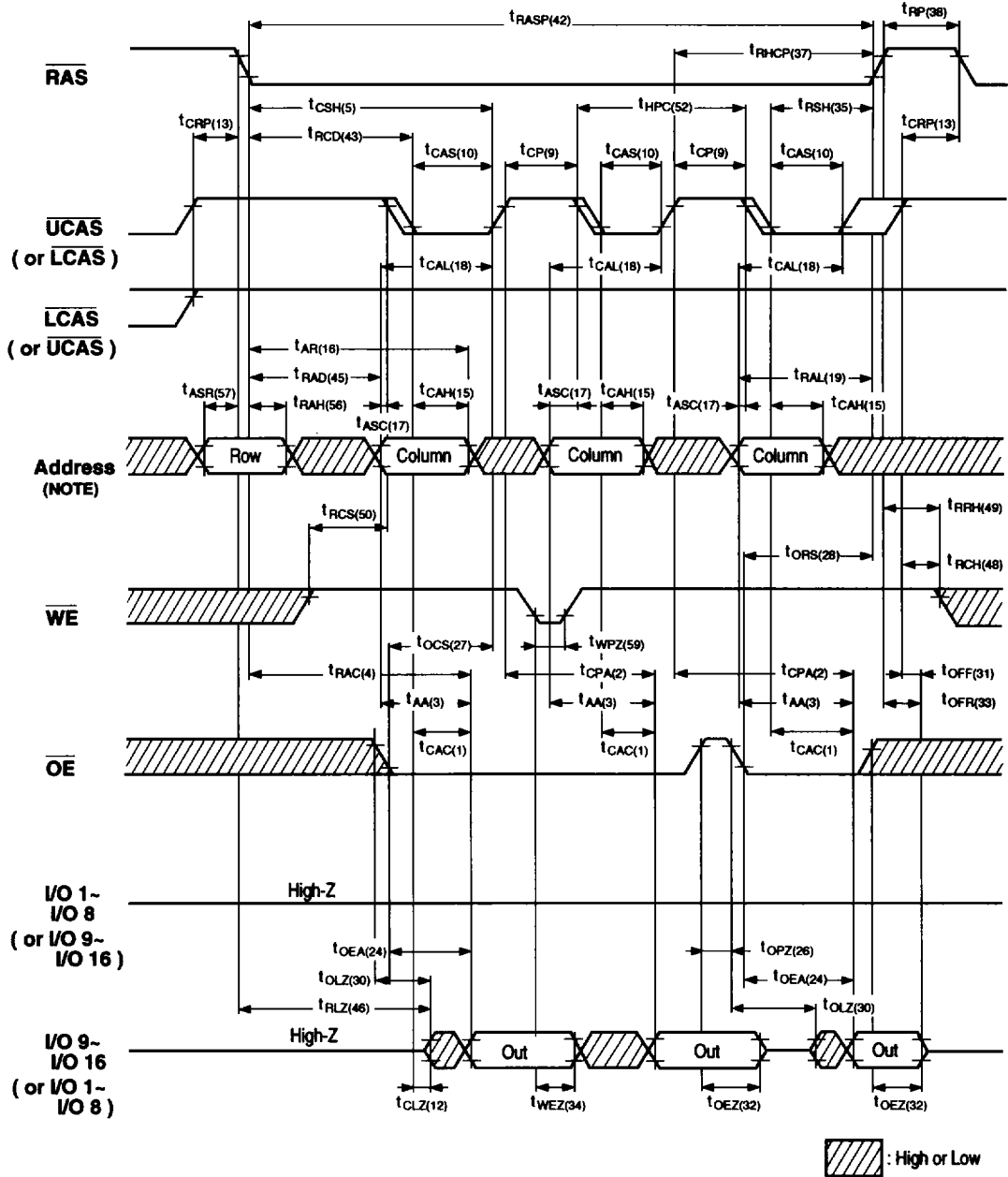
EDO (HYPER PAGE) MODE BYTE READ CYCLE



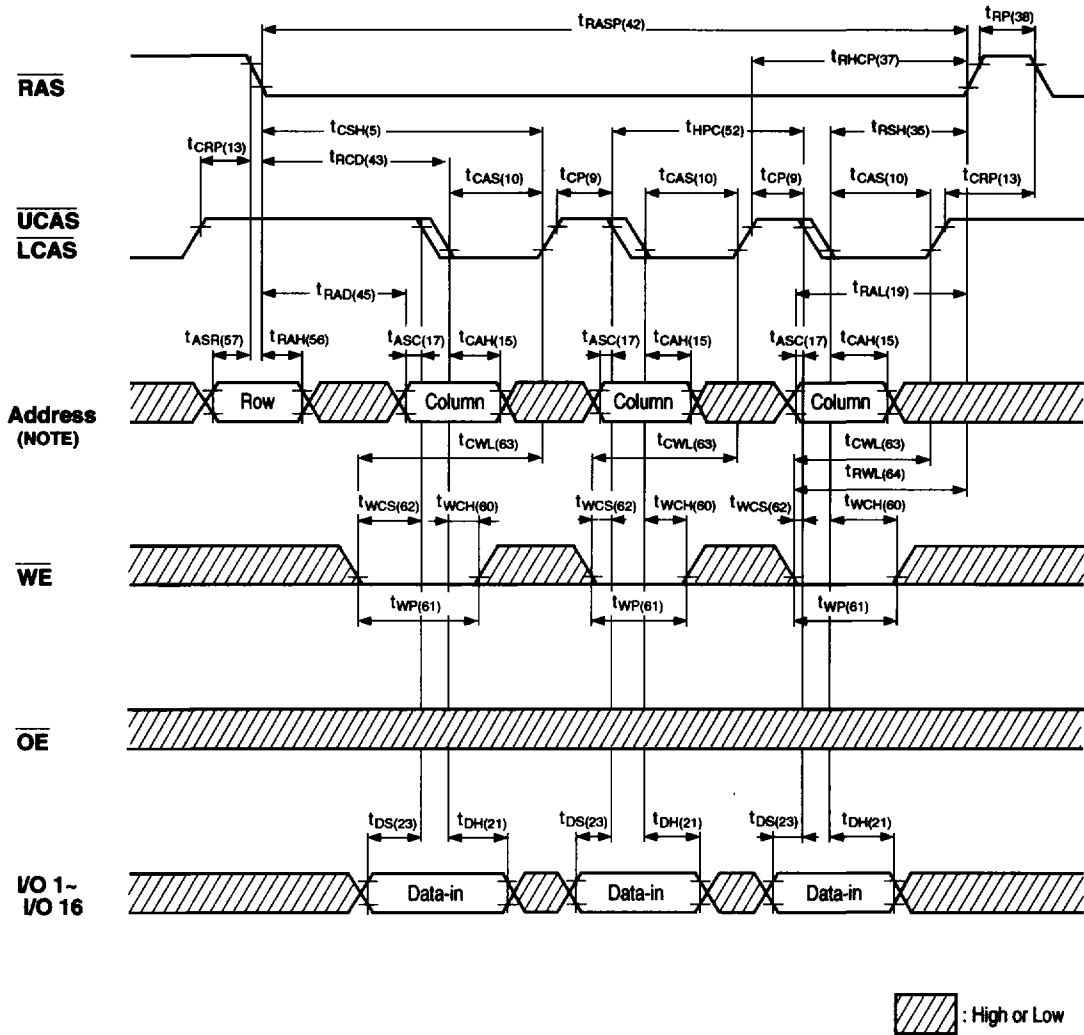
EDO (HYPER PAEGE) MODE WORD READ CYCLE (\overline{OE} AND \overline{WE} CONTROLLED OUTPUT)



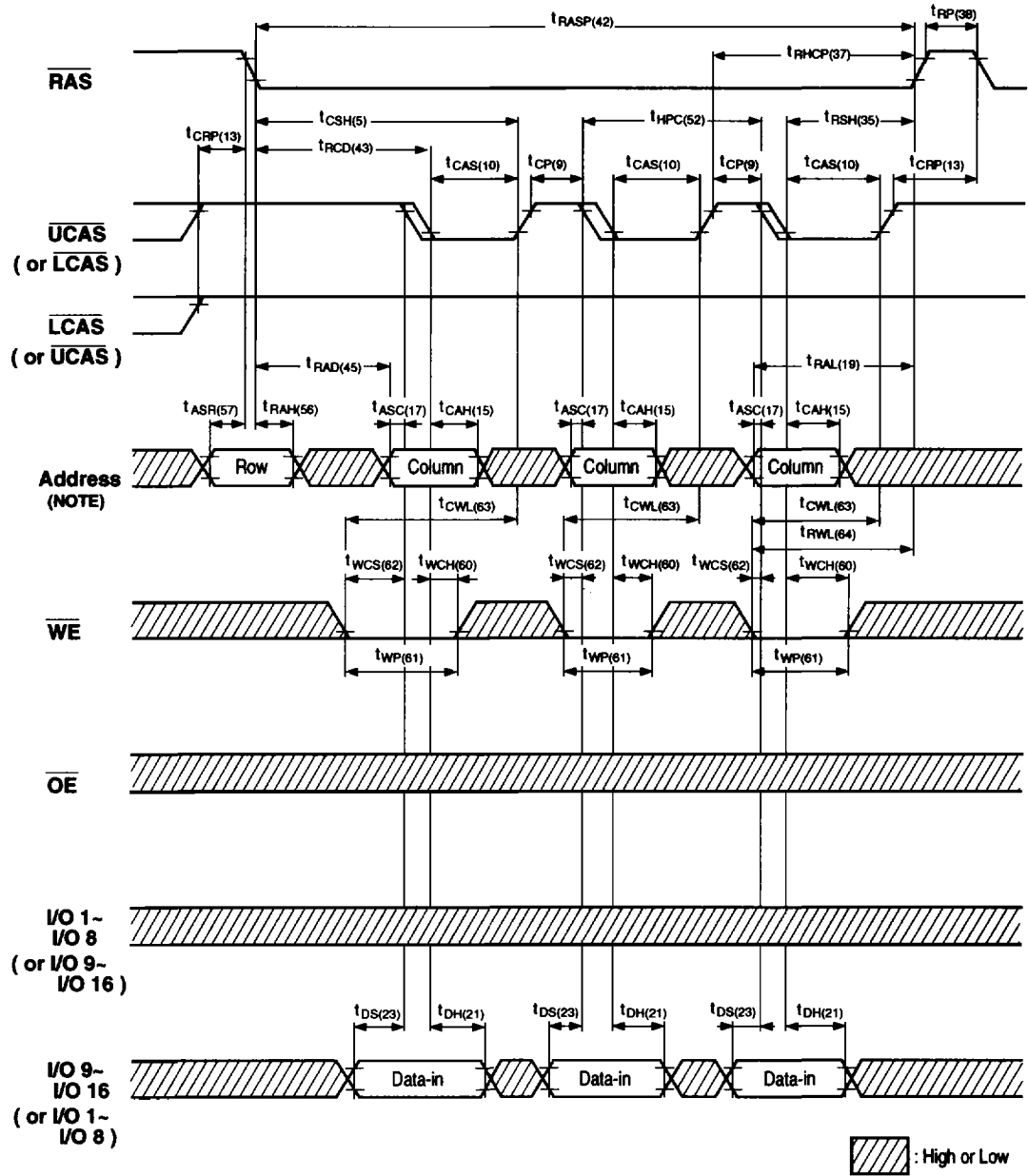
EDO (HYPER PAGE) MODE BYTE READ CYCLE (OE AND WE CONTROLLED OUTPUT)



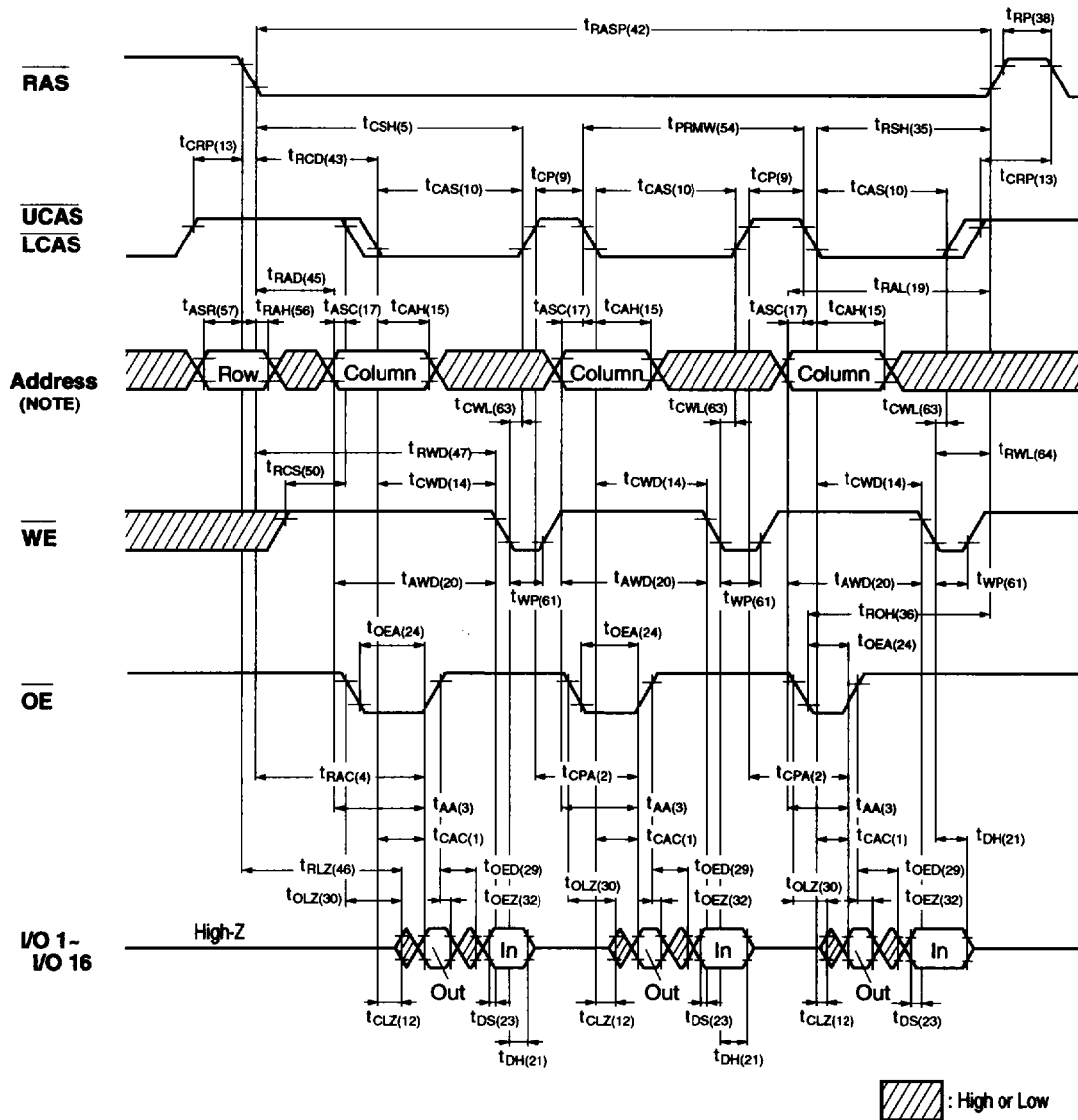
EDO (HYPER PAGE) MODE EARLY WORD WRITE CYCLE



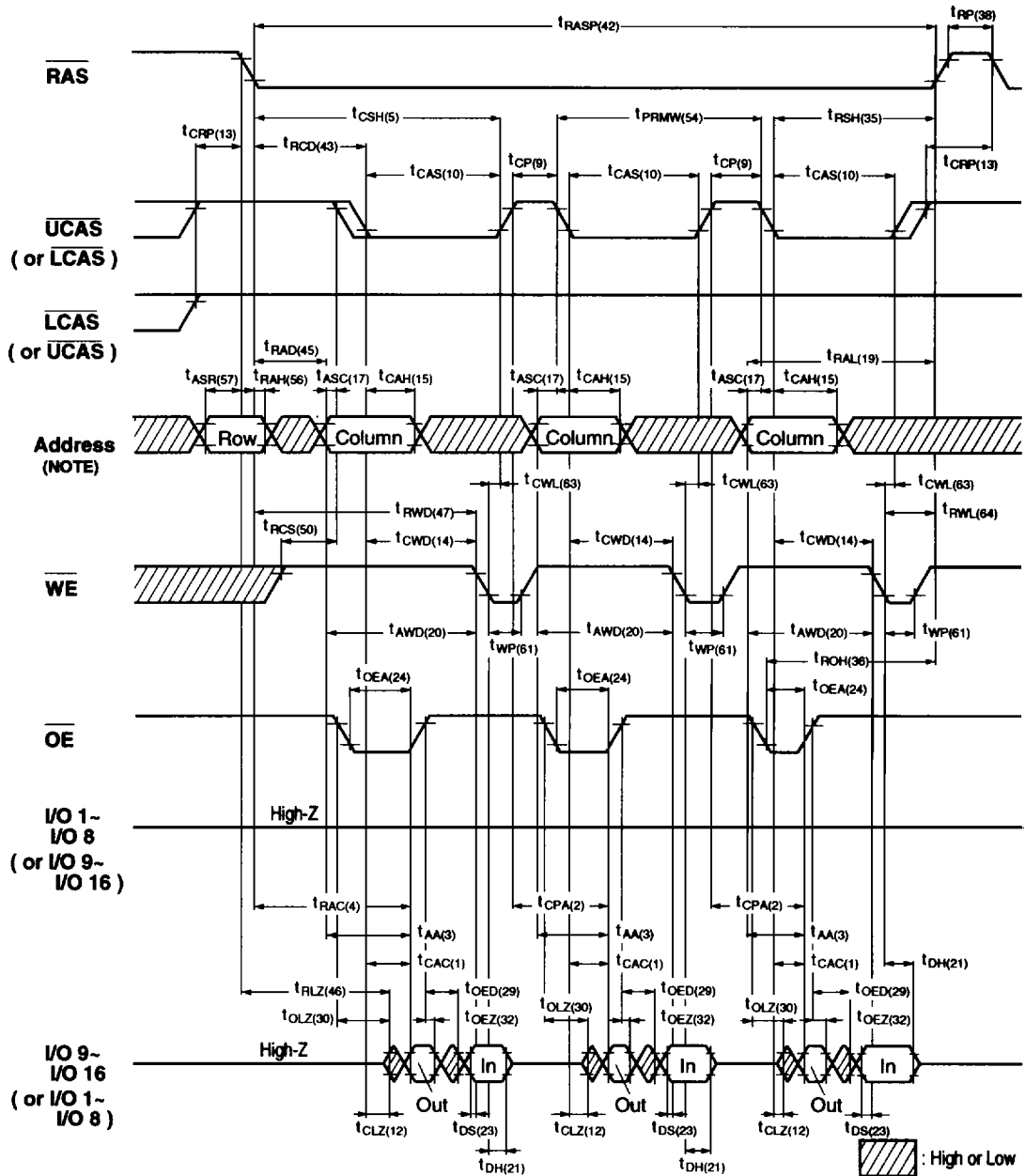
EDO (HYPER PAGE) MODE EARLY BYTE WRITE CYCLE



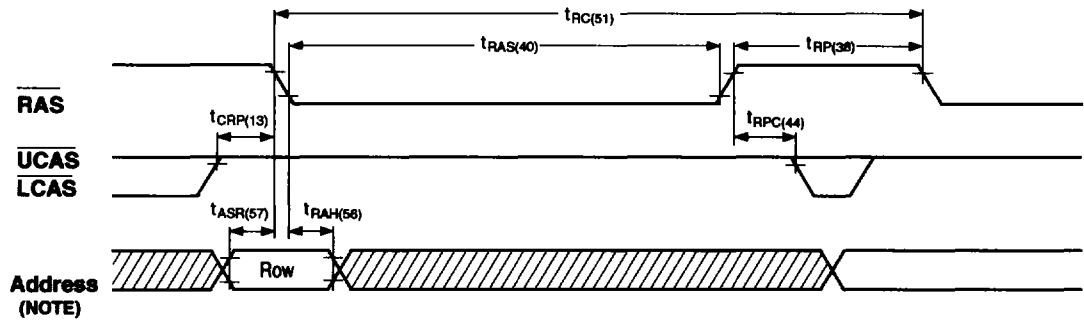
EDO (HYPER PAGE) MODE WORD READ-MODIFY-WRITE CYCLE



EDO (HYPER PAGE) MODE BYTE READ-MODIFY-WRITE CYCLE



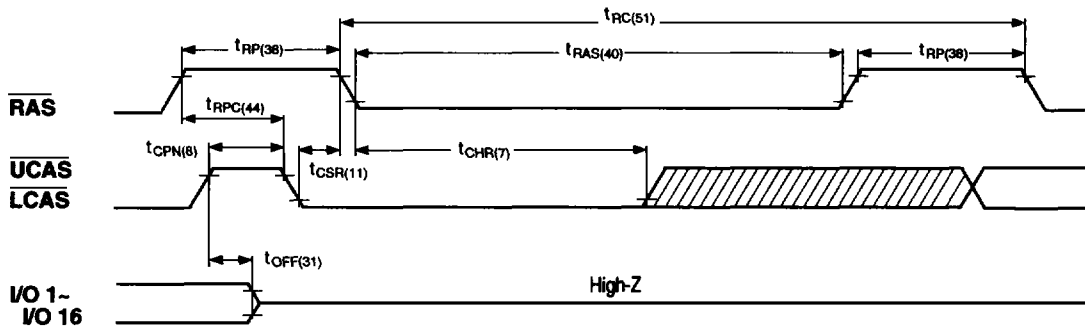
RAS ONLY REFRESH CYCLE



Note 2: \overline{WE} , \overline{OE} = Don't care.

 : High or Low

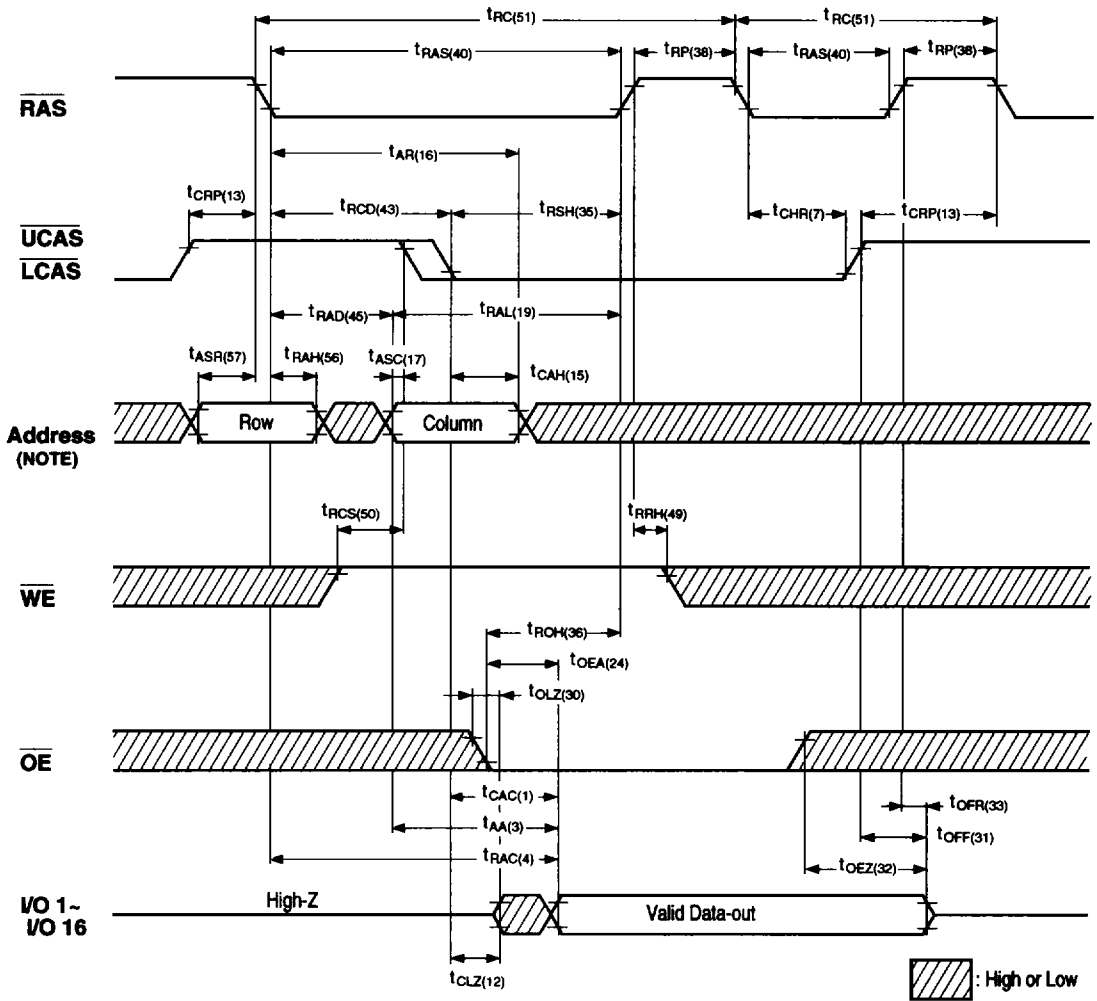
CAS BEFORE RAS REFRESH CYCLE



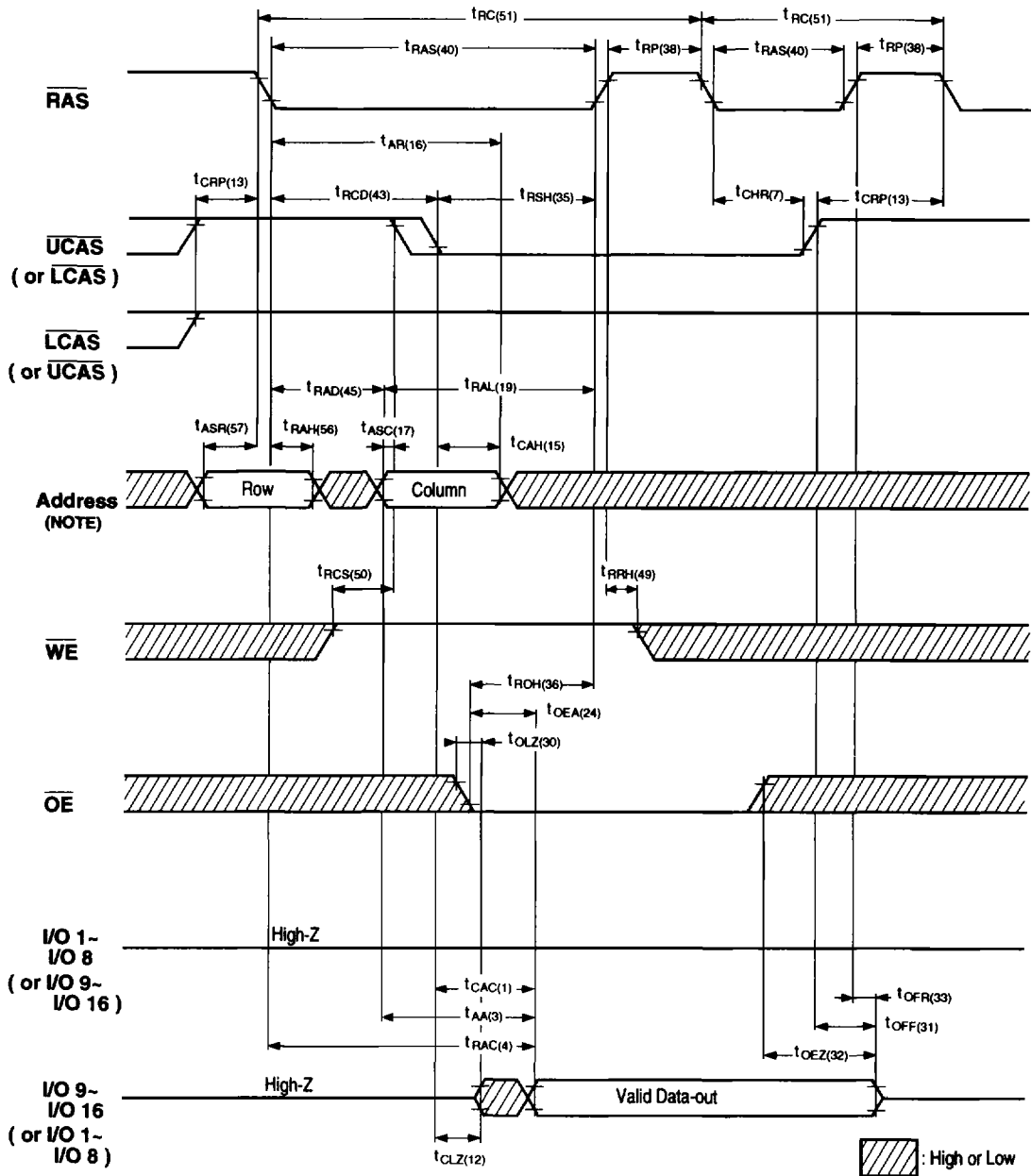
Note 3: \overline{OE} , Address = Don't care.

 : High or Low

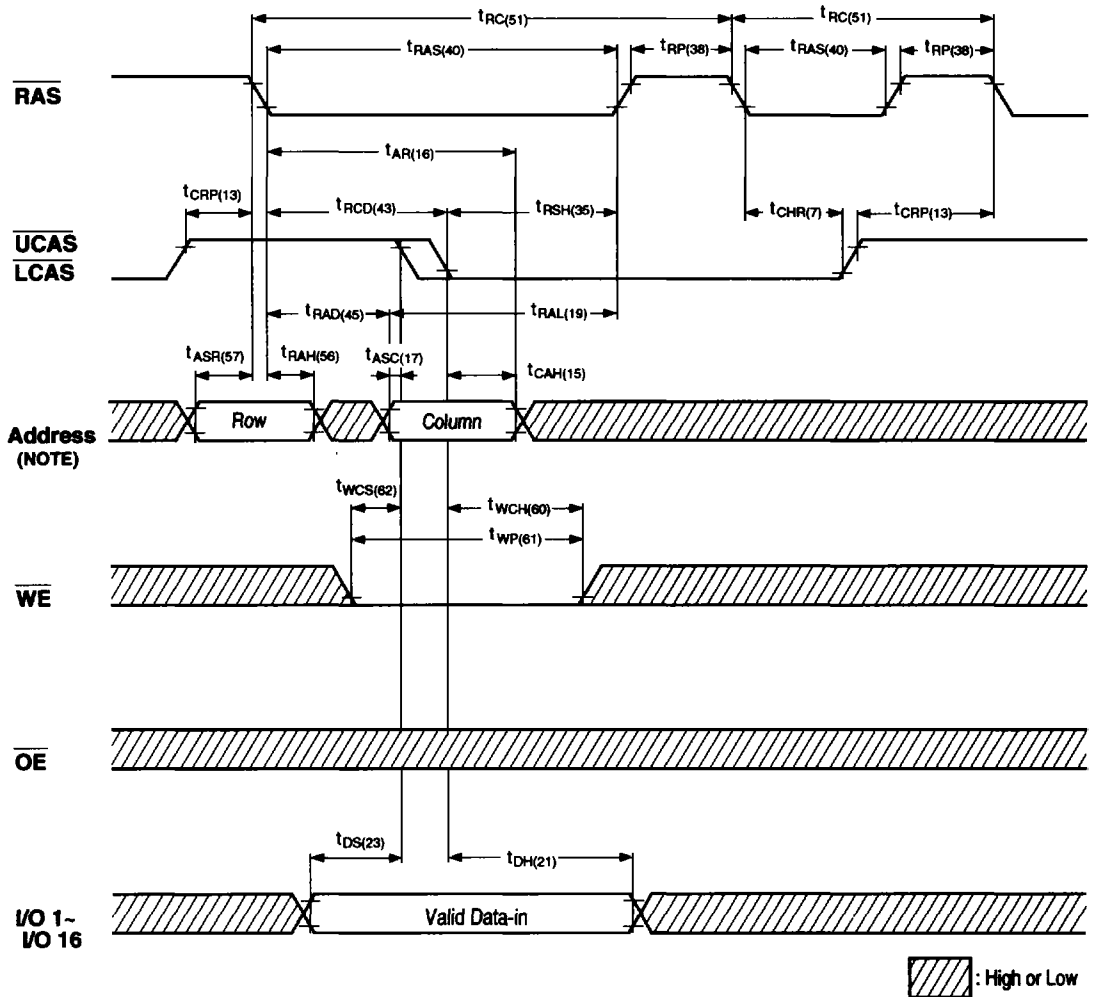
HIDDEN REFRESH CYCLE (WORD READ)



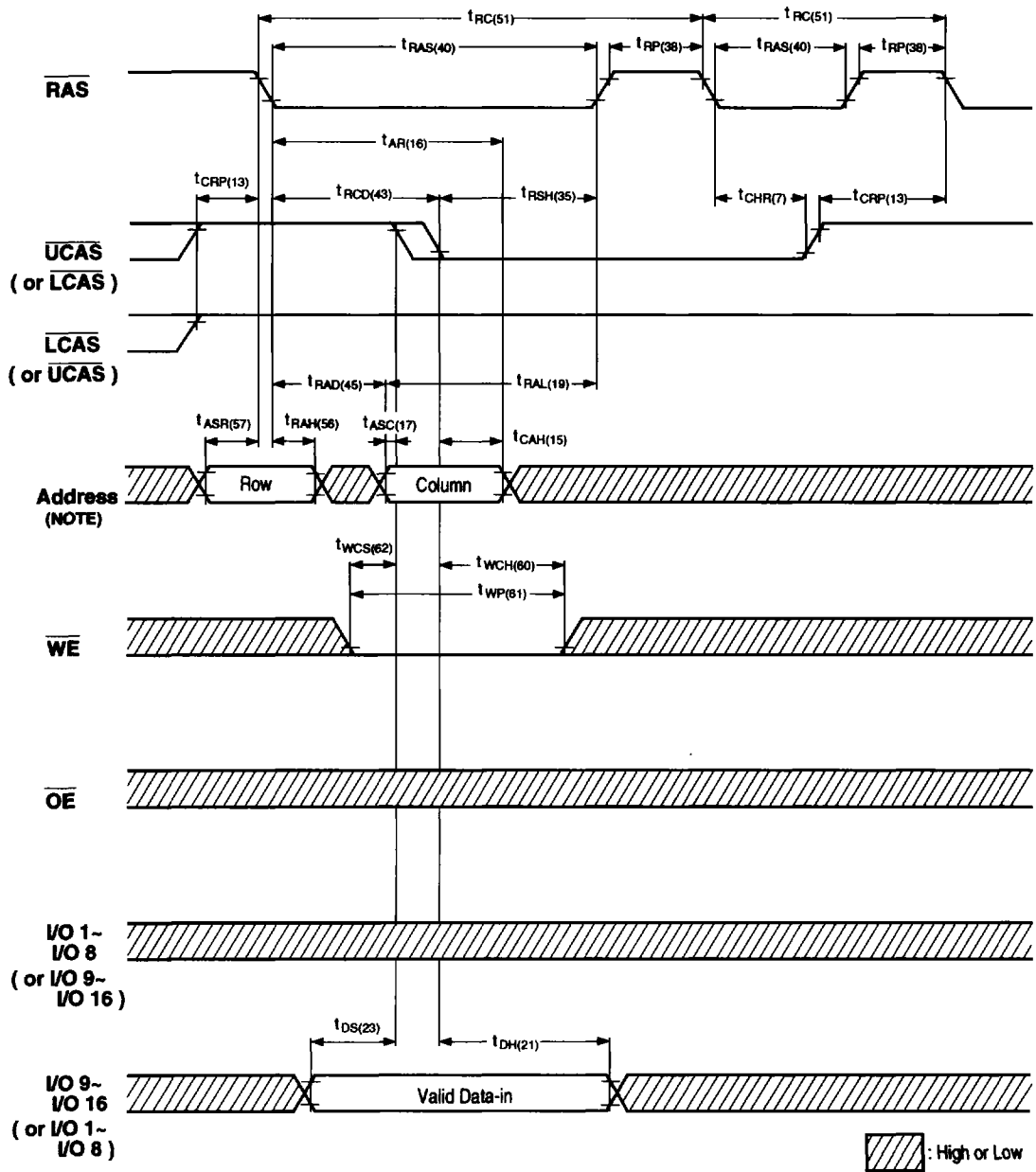
HIDDEN REFRESH CYCLE (BYTE READ)



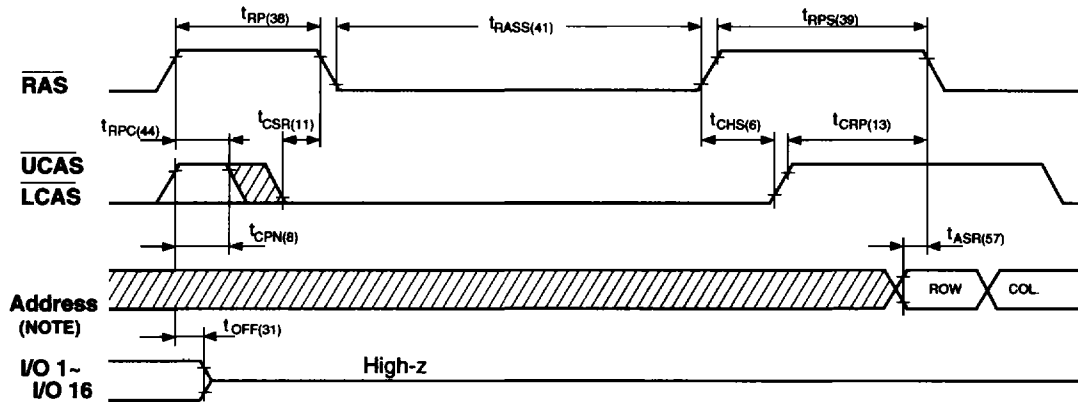
HIDDEN REFRESH CYCLE (EARLY WORD WRITE)



HIDDEN REFRESH CYCLE (EARLY BYTE WRITE)



SELF REFRESH MODE



Note 4: \overline{WE} , \overline{OE} = Don't care.

 : High or Low

■ The NN51V16165A/18165A (L version) has a Self Refresh Mode.

a. Entering the Self Refresh Mode:

The NN51V16165AL/18165AL Self Refresh Mode is entered by using \overline{CAS} before \overline{RAS} cycle and holding RAS and CAS signal "low" longer than 300 μ s.

b. Continuing the Self Refresh Mode:

The Self Refresh Mode is continuing by holding \overline{RAS} "low" after entering the Self Refresh Mode.

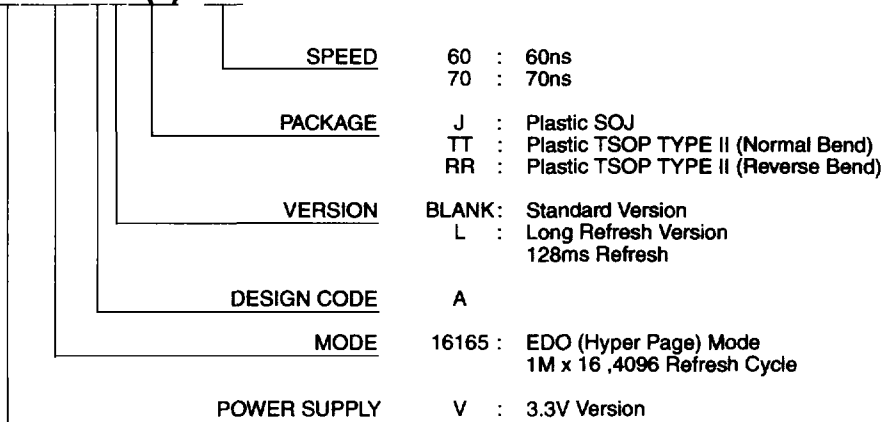
It does not depend on \overline{CAS} being "high" or "low" after entering the Self Refresh Mode to continue the Self Refresh Mode.

c. Exiting the Self Refresh Mode:

The NN51V16165AL/18165AL exits will exit the Self Refresh Mode when the \overline{RAS} signal is brought "high".

ORDERING INFORMATION

NN51V16165AXX(X) - XX



NN51V18165AXX(X) - XX

